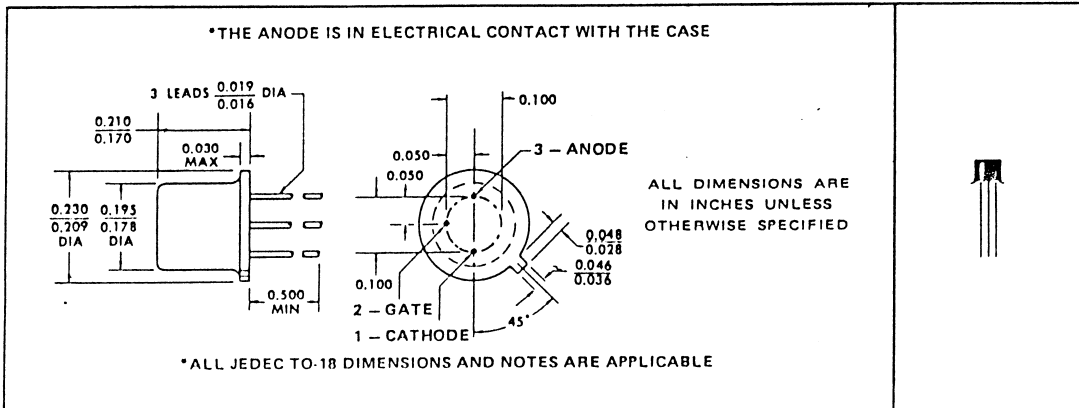


2N3004

P-N-P-N PLANAR SILICON REVERSE-BLOCKING TRIODE THYRISTOR

mechanical data

The devices are in a hermetically sealed welded case with a glass-to-metal seal between case and leads. Approximate weight is 0.35 grams.



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

	2N3004	UNIT
*Static Off-State Voltage, $V_D$ (See Note 1)	200	V
*Repetitive Peak Off-State Voltage, $V_{DRM}$ (See Note 1)	200	V
*Static Reverse Voltage, $V_R$ (See Note 2)	200	V
*Repetitive Peak Reverse Voltage, $V_{RRM}$ (See Note 2)	200	V
*Continuous or RMS On-State Current at (or below) 55°C Free-Air Temperature (See Note 3)	350	mA
*Average On-State Current (180° Conduction Angle) at (or below) 55°C Free-Air Temperature (See Note 4)	250	mA
*Surge On-State Current (See Note 5)	6	A
Peak Negative Gate Voltage	8	V
*Peak Positive Gate Current (Pulse Width < 8 ms)	250	mA
*Average Gate Power Dissipation	100	mW
*Operating Free-Air Temperature Range	-65 to 150	°C
*Storage Temperature Range	-65 to 200	°C
*Lead Temperature 1/16 Inch from Case for 10 Seconds	300	°C

- NOTES: 1. These values apply when the gate-cathode resistance  $R_{GK} < 1 \text{ k}\Omega$ .  
 2. These values apply when the gate-cathode resistance  $R_{GK} < \infty$ .  
 3. This value applies for continuous d-c or single-phase, 60-Hz, half-sine-wave operation with resistive load. Above 55°C, derate according to Figure 1.  
 4. This value may be applied continuously under single-phase, 60-Hz, half-sine-wave operation with resistive load. Above 55°C, derate according to Figure 1.  
 5. This value applies for one 60-Hz half sine wave when the device is operating at (or below) rated values of peak reverse voltage and on-state current. Surge may be repeated after the device has returned to original thermal equilibrium.  
 \*JEDEC registered data. This data sheet contains all applicable registered data in effect at the time of publication.

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$I_D$ Static Off-State Current	$V_D = \text{Rated } V_D, R_{GK} = 1 \text{ k}\Omega$			0.1	$\mu\text{A}$
	$V_D = \text{Rated } V_D, R_{GK} = 1 \text{ k}\Omega, T_A = 150^\circ\text{C}$			100	
$I_R$ Static Reverse Current	$V_R = \text{Rated } V_R, R_{GK} = \infty$			0.1	$\mu\text{A}$
	$V_R = \text{Rated } V_R, R_{GK} = \infty, T_A = 150^\circ\text{C}$			100	
$I_G$ Gate Current	$V_G = -5 \text{ V}, I_A = 0$			-5	$\mu\text{A}$
$I_{GT}$ Gate Trigger Current	$V_{AA} = 5 \text{ V}, R_L = 12 \Omega, t_{p(g)} \geq 10 \mu\text{s}$			5	$\mu\text{A}$
$V_{GT}$ Gate Trigger Voltage	$V_{AA} = 5 \text{ V}, R_L = 12 \Omega, t_{p(g)} \geq 10 \mu\text{s}, T_A = -65^\circ\text{C}$			0.9	V
	$V_{AA} = 5 \text{ V}, R_L = 12 \Omega, t_{p(g)} \geq 10 \mu\text{s}$			0.55	
	$V_{AA} = 5 \text{ V}, R_L = 12 \Omega, t_{p(g)} \geq 10 \mu\text{s}, T_A = 150^\circ\text{C}$			0.7	
$I_H$ Holding Current	$R_{GK} = 1 \text{ k}\Omega, R_L = 2 \text{ k}\Omega$			1.2	mA
	$R_{GK} = 1 \text{ k}\Omega, R_L = 2 \text{ k}\Omega, T_A = -65^\circ\text{C}$			4	
$V_T$ On-State Voltage	$I_T = 350 \text{ mA}, R_{GK} \geq 1 \text{ k}\Omega$ , See Note 6			1.2	V
$dv/dt$ Critical Rate of Rise of Off-State Voltage	$V_D = 1 \text{ V}$			400	V/ $\mu\text{s}$

NOTE 6: The initial instantaneous value is measured using pulse techniques. On-state pulse width = 300  $\mu\text{s}$ , PRR = 100 pps.  
 \*JEDEC registered data

